

Search Notes

Application/Control No.

10/820,420

Examiner

John D. Lee

Applicant(s)/Patent under
Reexamination

REED ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	10,37,122	12/20/2005	JDL
359	326,332	12/20/2005	JDL
372	21,22	12/20/2005	JDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	12/20/2005	JDL